


<b>Search Notes</b>  	<b>Application/Control No.</b>  10003113	<b>Applicant(s)/Patent Under Reexamination</b>  SEKIGUCHI ET AL.
	<b>Examiner</b>  Hung, Yubin	<b>Art Unit</b>  2624

SEARCHED			
Class	Subclass	Date	Examiner
382	166,190,199,232,233,243,254,263,264,266,275	9/17/08	YH
348	384.1	9/17/08	YH
358	426.01	9/17/08	YH
375	240	9/17/08	YH
708	203	9/17/08	YH

SEARCH NOTES		
Search Notes	Date	Examiner
EAST text search (USPGPUB, USPAT, EPO, JPO, DERWENT, IBM-TDB)	9/17/08	YH
Inventor search	2/13/07	YH
Assignee search	2/13/07	YH
ACM	2/25/07	YH
SPIE	2/25/07	YH
IEEE Xplore	2/25/07	YH
Inventor and assignee search	2/13/07	YH

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

	/YUBIN HUNG/ Primary Examiner.Art Unit 2624
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